Abstracts

Full-Wave Analysis of the Influence of Conductor Shape and Structure Details on Losses in Coplanar Waveguide

W. Schroeder and I. Wolff. "Full-Wave Analysis of the Influence of Conductor Shape and Structure Details on Losses in Coplanar Waveguide." 1995 MTT-S International Microwave Symposium Digest 95.3 (1995 Vol. III [MWSYM]): 1273-1276.

The influence of technological details like two-layer structure of conducting strips, layer misalignment, non-rectangular conductor shape, dielectric cover or support layers on losses in CPW with small lateral dimensions is investigated by means of the hybrid-wave Boundary Integral Equation Method (BIEM). A short account of recent developments in this method, as required for this investigation, is given with focus on two concepts of general interest, the Method of Least Squares with Intermediate Projection (MLSIP) and a regularization approach.

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